

**Notice of References Cited**

Application/Control No.

10/788,765

Applicant(s)/Patent Under  
Reexamination  
CHEN ET AL.

Examiner

Tianjie Chen

Art Unit

2627

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,342,752 B1	03-2008	Zhang et al.	360/324.12
*	B	US-6,144,534 A	11-2000	Xue et al.	360/327.31
*	C	US-6,172,859 B1	01-2001	Watanabe et al.	360/327.3
*	D	US-6,185,081 B1	02-2001	Simion et al.	360/327.3
*	E	US-6,449,135 B1	09-2002	Ding et al.	360/327.31
*	F	US-5,742,459	04-1998	Shen et al.	360/327.32
*	G	US-5,739,987	04-1998	Yuan et al.	360/327.32
*	H	US-5,434,826 A	07-1995	Ravipati et al.	367/140
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.